D2804, MARCH 1984-REVISED JUNE 1989

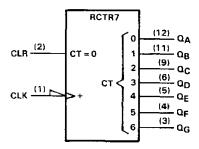
- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs
- Dependable Texas Instruments Quality and Reliability

description

The 'HC4024 is an asynchronous 7-stage binary counter designed with an input pulse-shaping circuit. The outputs of all stages are available externally. A high clear signal asynchronously clears the counter and resets all outputs low. The count is advanced on the high-to-low transition of the clock pulse. Applications include time-delay circuits, counter controls, and frequency-dividing circuits.

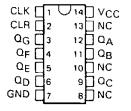
The SN54HC4024 is characterized for operation over the full military temperature range of $-55\,^{\circ}\text{C}$ to 125 $^{\circ}\text{C}$. The SN74HC4024 is characterized for operation from $-40\,^{\circ}\text{C}$ to 85 $^{\circ}\text{C}$.

logic symbol†

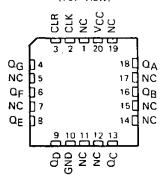


[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN54HC4024 . . . J PACKAGE SN74HC4024 . . . D OR N PACKAGE (TOP VIEW)



\$N54HC4024 . . . FK PACKAGE (TOP VIEW)

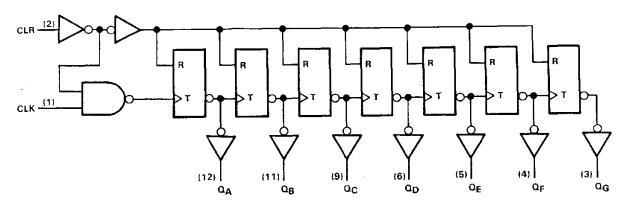


NC-No internal connection

Pin numbers shown are for D, J, and N packages.

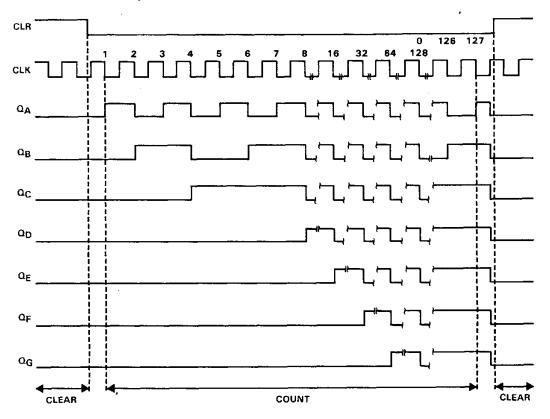
SN54HC4024, SN74HC4024 ASYNCHRONOUS 7-BIT BINARY COUNTERS

logic diagram (positive logic)



Pin numbers shown are for D, J, and N packages.

typical clear and count sequence



SN54HC4024, SN74HC4024 ASYNCHRONOUS 7-BIT BINARY COUNTERS

absolute maximum ratings over operating free-air temperature range†

Supply voltage, VCC
Input clamp current, IJK (V_I < 0 or V_I > V_{CC})
Output clamp current, IOK (VO < 0 or VO > VCC ±20 mA
Continuous output current, I_0 ($V_0 = 0$ to V_{CC})
Continuous current through VCC or GND pins
Lead temperature 1,6 mm (1/16 in) from case for 60 s: FK or J package 300°C
Lead temperature 1,6 mm (1/16 in) from case for 10 s: D or N package 260 °C
Storage temperature range65 °C to 150 °C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SN54HC4024			SN74HC4024				
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		2	5	6	2	5	6	V	
		V _{CC} = 2 V	1.5			1.5				
V_{IH}	High-level input voltage	$V_{CC} = 4.5 V$	3.15			3.15			V	
		$V_{CC} = 6 V$	4.2			4.2				
VIL	Low-level input voltage	V _{CC} = 2 V	. 0		0.3	0	·	0.3		
		V _{CC} = 4.5 V	0		0.9	0		0.9	V	
		V _{CC} = 6 V	0		1.2	0		1.2		
V _I	Input voltage		0		Vcc	0		Vcc	V	
۷o	Output voltage		0		Vcc	0		Vcc	V	
	Input transition (rise and fall) times	V _{CC} = 2 V	0		1000	0		1000		
tt		$V_{CC} = 4.5 V$	0		500	0		500	ns	
		V _{CC} = 6 V	0		400	0		400		
T_A	Operating free-air temperature		- 55		125	-40		85	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vcc	TA = 25°C			SN54HC4024		SN74HC4024		LIBUT
· AIIAINETEN	TEST CONDITIONS		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		2 V	1.9	1.998		1.9		1.9		
	$V_{\parallel} = V_{\parallel H}$ or $V_{\parallel L}$, $I_{OH} = -20 \mu A$	4.5 V	4.4	4.499		4.4		4.4		
∨он [6 V	5.9	5.999		5.9		5.9		V
1	$V_{\parallel} = V_{\parallel H}$ or $V_{\parallel L}$, $I_{OH} = -4$ mA	4.5 V	3.98	4.30		3.7		3.84		
	$V_{I} = V_{IH}$ or V_{IL} , $I_{OH} = -5.2$ mA	6 V	5.48	5.80		5.2		5.34		-
	$V_{I} = V_{IH}$ or V_{IL} , $I_{OL} = 20 \mu A$	2 V		0.002	0.1		0.1		0.1	V
		4.5 V		0.001	0.1		0.1		0.1	
Vol [6 V		0.001	0.1	l	0.1		0.1	
Į.	$V_{\parallel} = V_{\parallel H}$ or $V_{\parallel L}$, $ OL = 4$ mA	4.5 V		0.17	0.26	1	0.4		0.33	
	VI = VIH or VIL. IOL = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
l ₁	V _I = V _{CC} or 0	6 V		±0.1	± 100	±	1000	±	1000	nΑ
Icc	$V_1 = V_{CC}$ or 0, $I_0 = 0$	6 V			8		160		80	μА
Ci		2 to 6 V	7	3	10		10		10	рF

SN54HC4024, SN74HC4024 ASYNCHRONOUS 7-BIT BINARY COUNTERS

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			W	T _A =	25°C	SN54F	IC4024	SN74H	C4024	116117
			vcc	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
			2V	0	5.5	0	3.7	0	4.3	
f _{clock}	Clock frequency		4.5 V	0	28	0	19	0	22	MHz
			6 V	0	33	0	22	0	25	
	Pulse duration		2 V	90		135		115		
		CLK high or low	4.5 V	18		27		23		ns
			6 V	15		23		20		
^t w			2 V	80		120		100		
		CLR high	4.5 V	16		24		20		ns
			6 V	14		20		17		
	Catura time a CLD la		2 V	80		120		100		
t _{su}	Setup time, CLR low		4.5 V	16		24		20		ns
	before CLK+		6 V	14		20		17		

switching characteristics over recommended operating free-air temperature range (unless otherwise noted), $C_L = 50 \text{ pF}$ (see Note 1)

PARAMETER	FROM TO			T _A = 25°C			SN54HC4024		SN74HC4024		
PANAIVICIEN	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	5.5	10		3.7		4.3		
fmax		QA	4.5 V	28	50		19		22		MHz
			6 V	33	60		22		26		
			2 V		56	120		180	·	150	
^t pd	CLK	QΑ	4.5 V		16	24		36		30	ns
			6 V		12	20		31		26	
			2 V		61	130		195		165	
[†] PHL	CLR Any 4.	4.5 V		17	26		39		32	ns	
			6 V		13	22		33	}	28	
			2 V		28	75		110		95	
tt		Q _A	4.5 V		8	15		22		19	ns
			6 V		6	13	1	19		16	

C _{pd}	Power dissipation capacitance	No load, T _A = 25 °C	40 pF typ

Note 1: Load circuits and voltage waveforms are shown in Section 1.

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